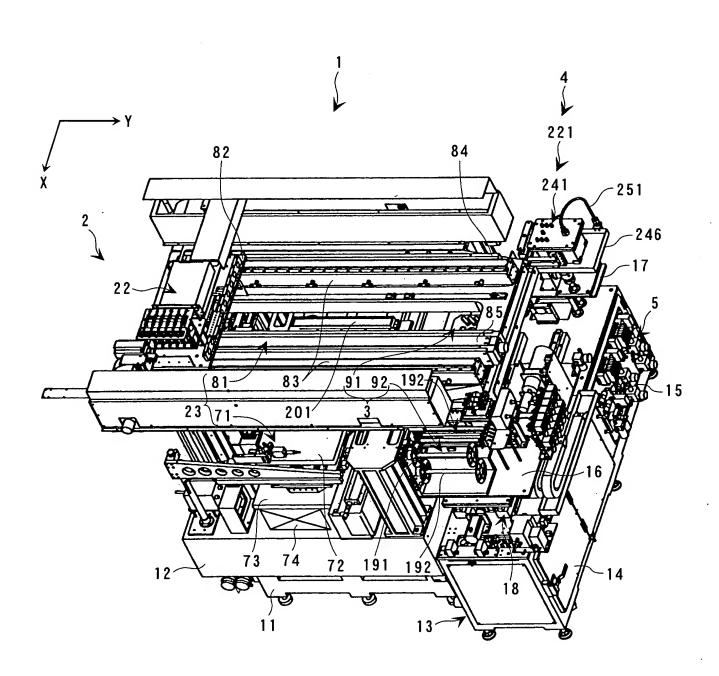
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Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

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F I G. 1

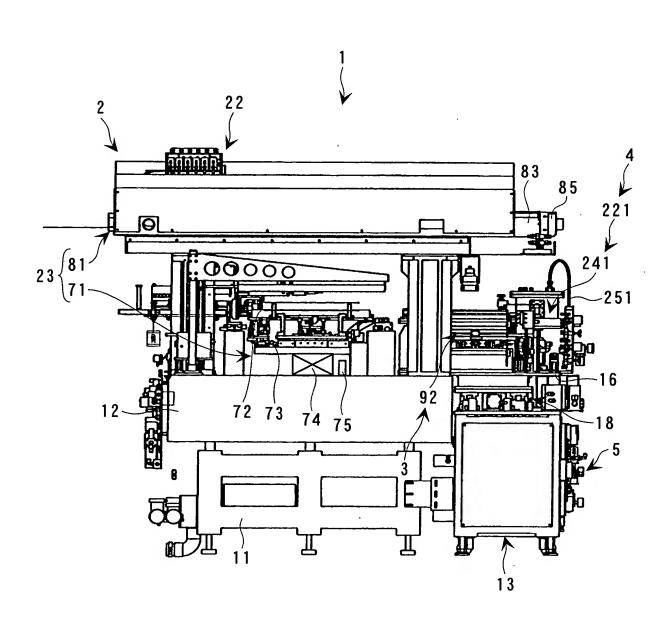


Title: METHOD OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS; IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

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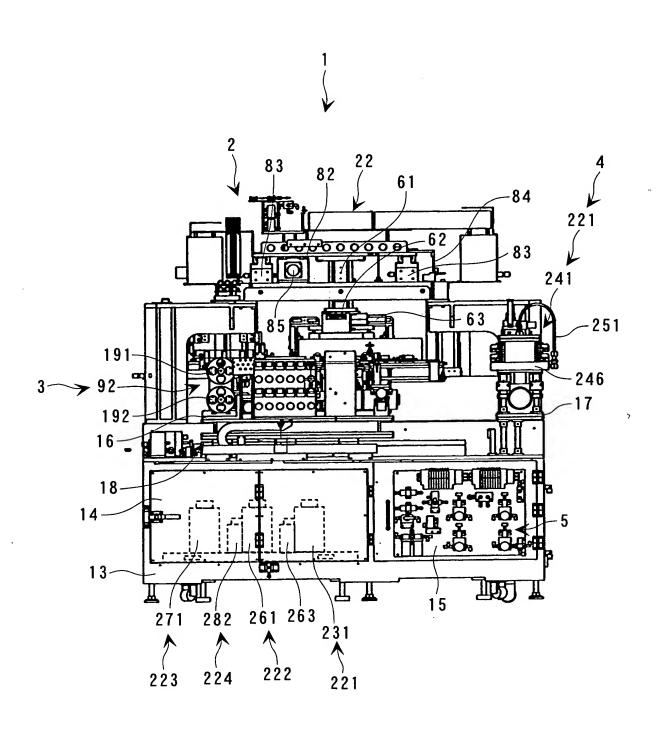
F I G. 2



ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

F I G. 3

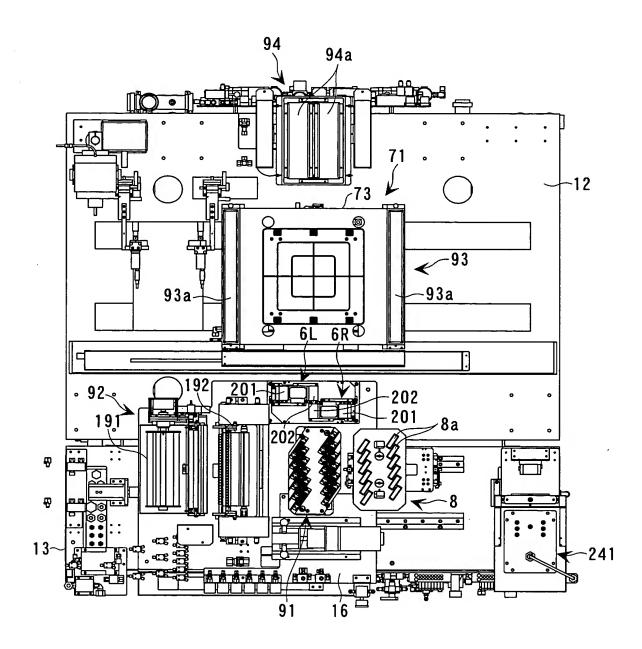


ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

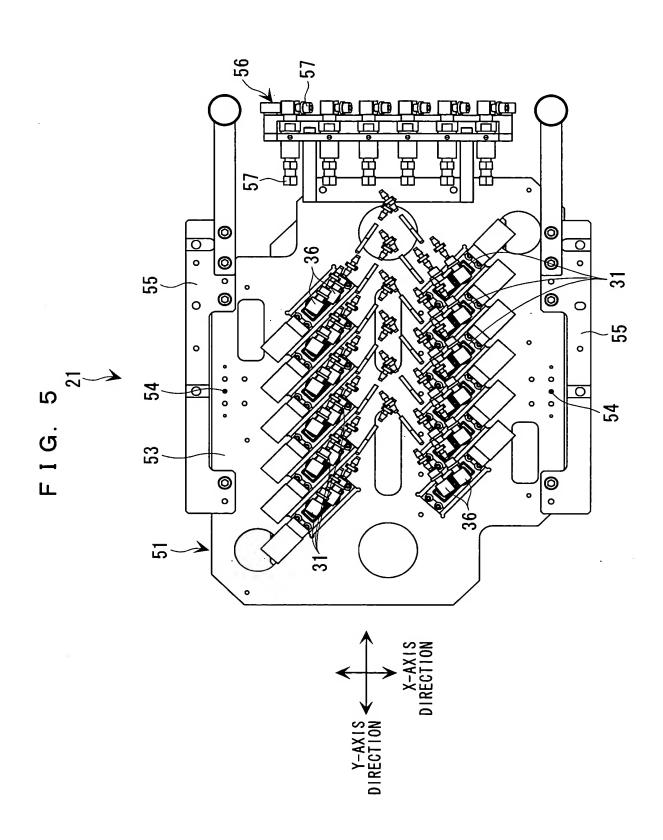
Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

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F I G. 4



Title: METHOD OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS; IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING

ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

FIG. 6A

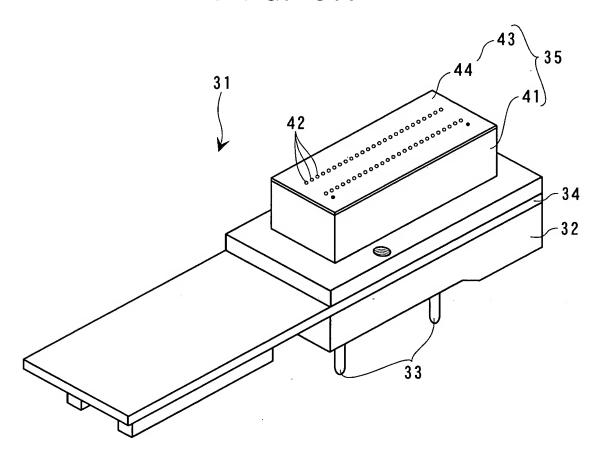
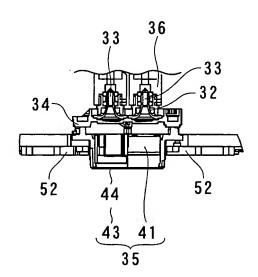


FIG. 6B

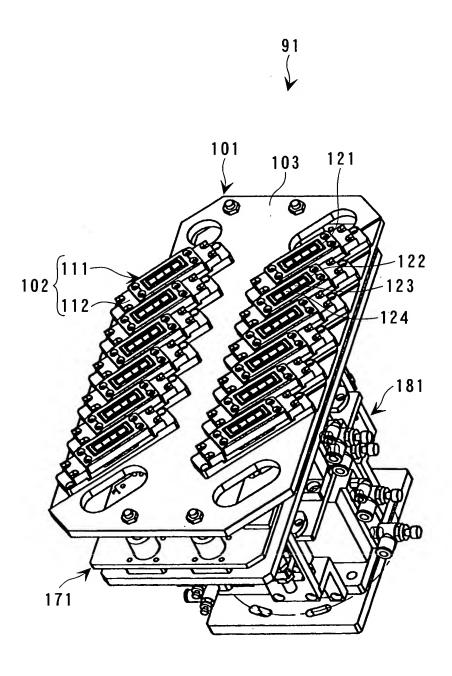


IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

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## FIG. 7

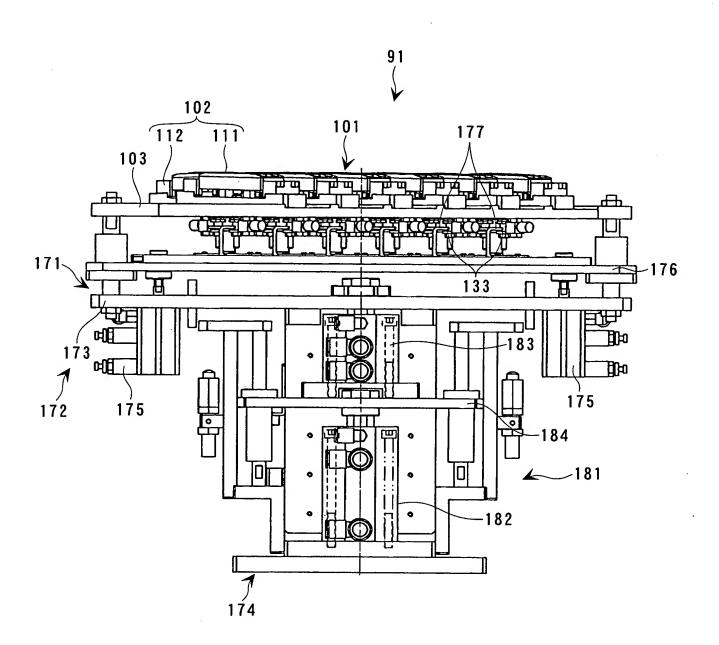


ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

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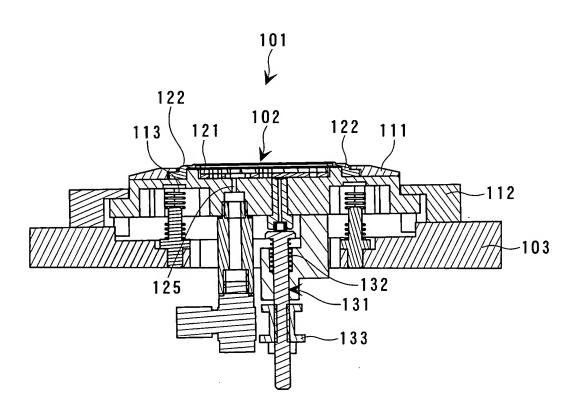
F I G. 8



IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

FIG. 9

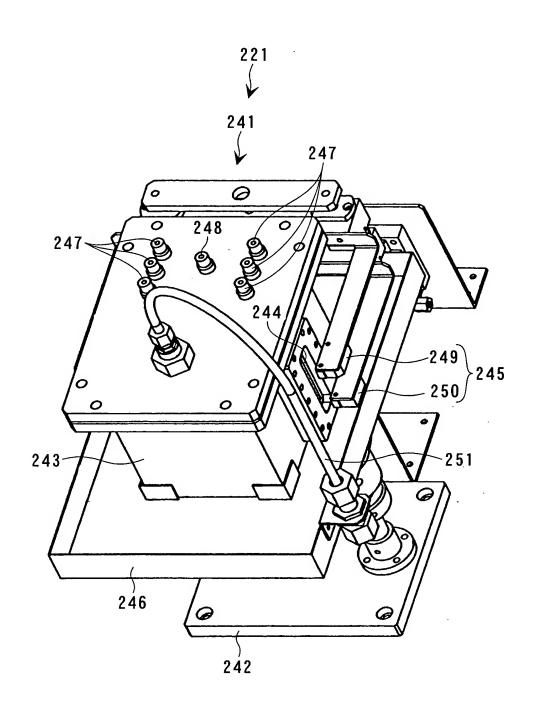


Title: METHOD OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS;
IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT
Inventor: Shinichi NAKAMURA

Atty. Ref.: 9319H-000586

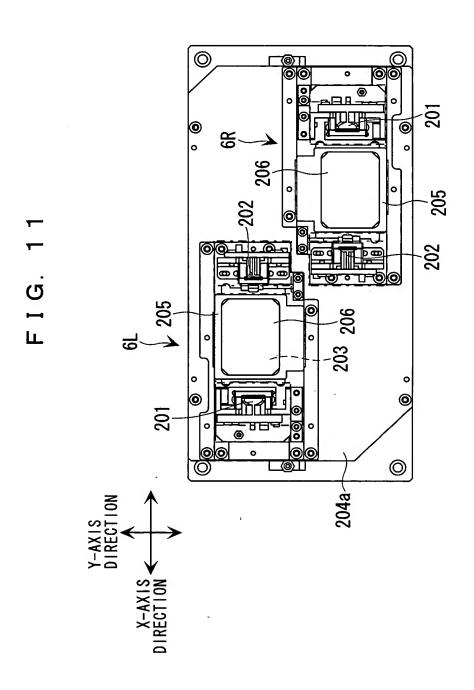
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## F I G. 10



IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT
Inventor: Shinich NAKAMURA

Atty. Ref.: 9319H-000586

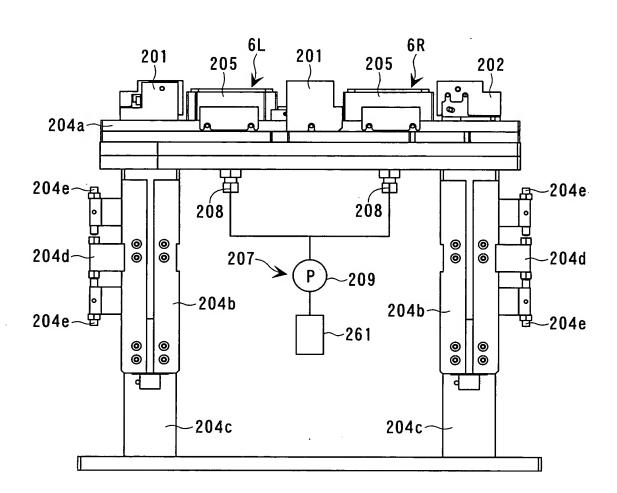


ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

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FIG. 12

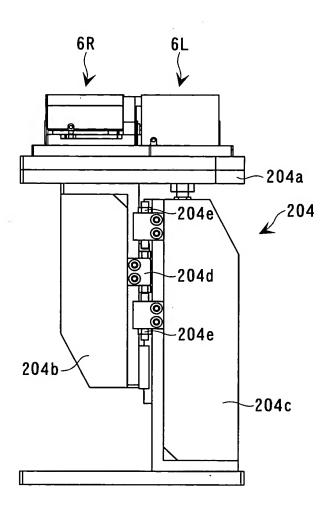


IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

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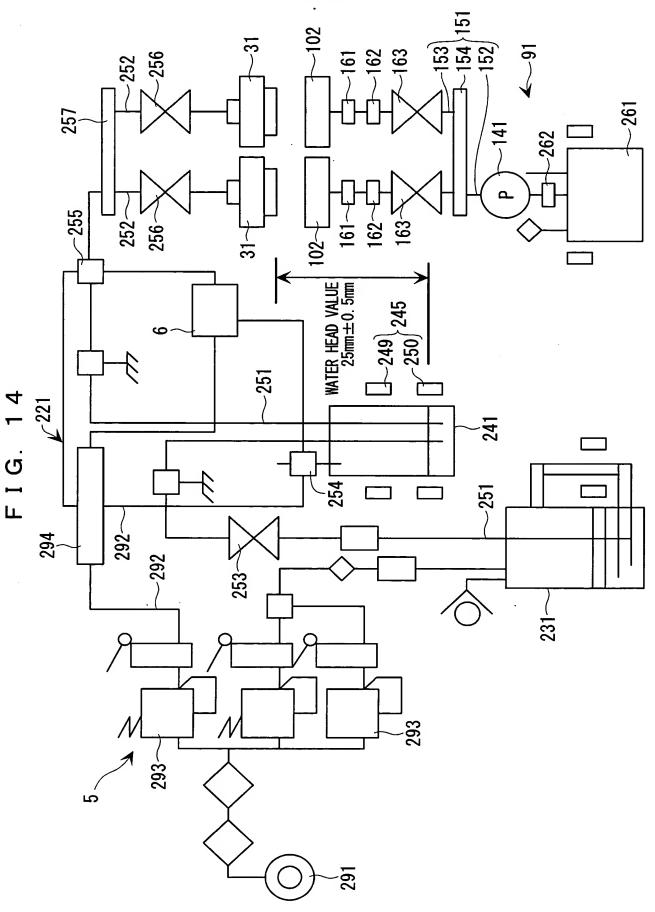
FIG. 13



IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

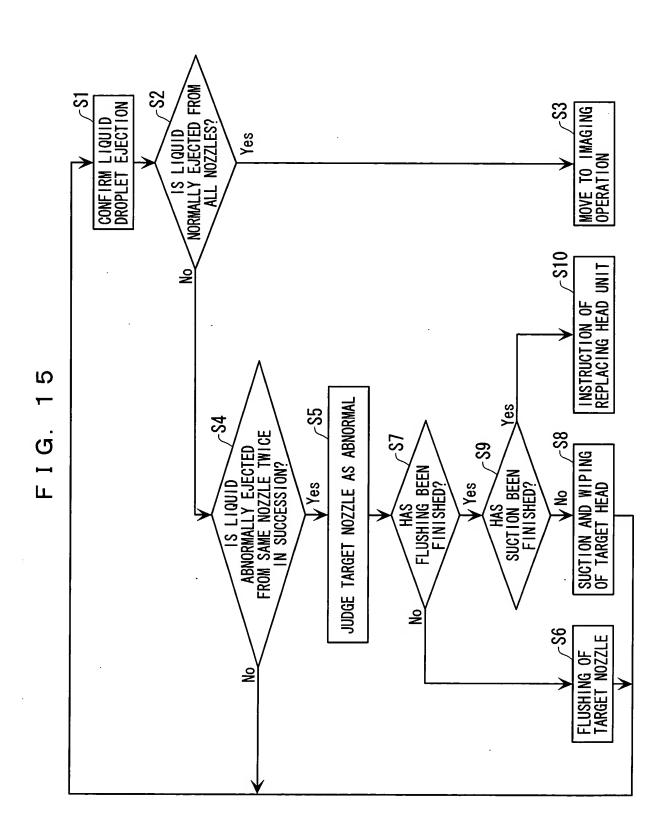
Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586





Intel: METHOD OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS; IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

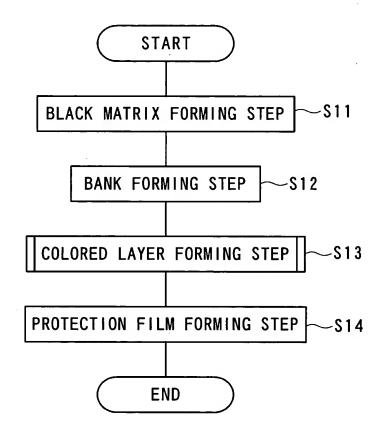
Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586 16/33

FIG. 16

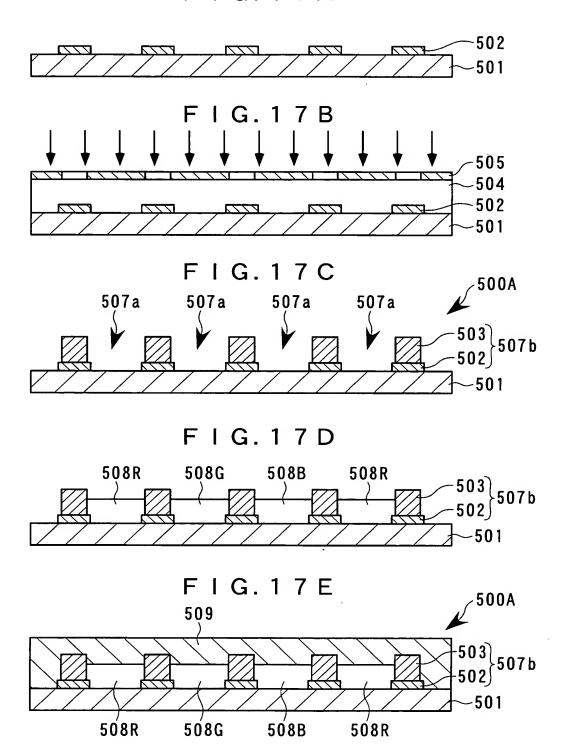


ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

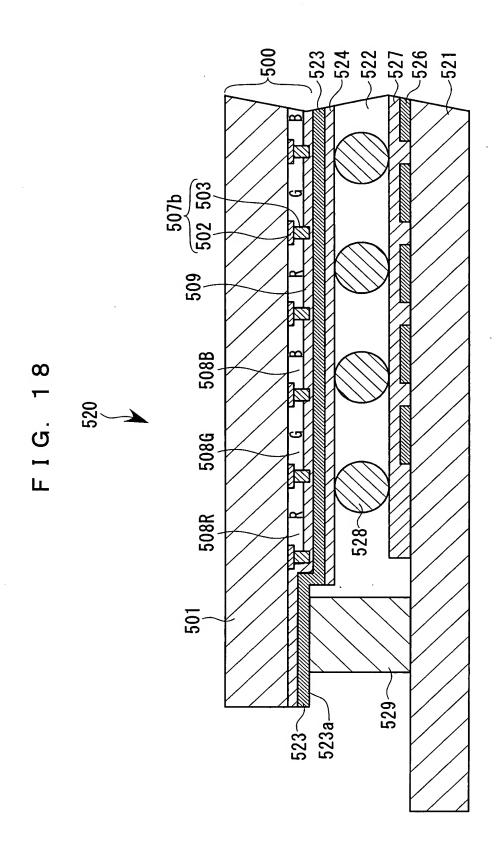
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## F I G. 17A

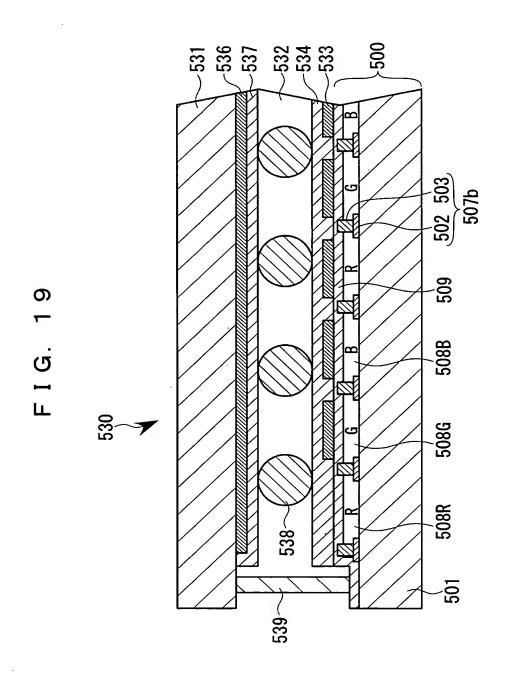


IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



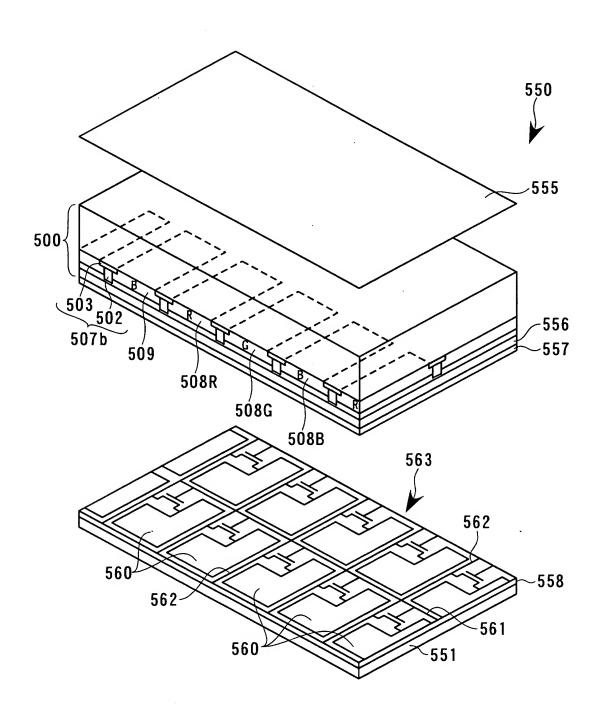
Title: METHOD OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS;
IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT
Inventor: Shinichi NAKAMURA
Atty. Ref.: 9319H-000586



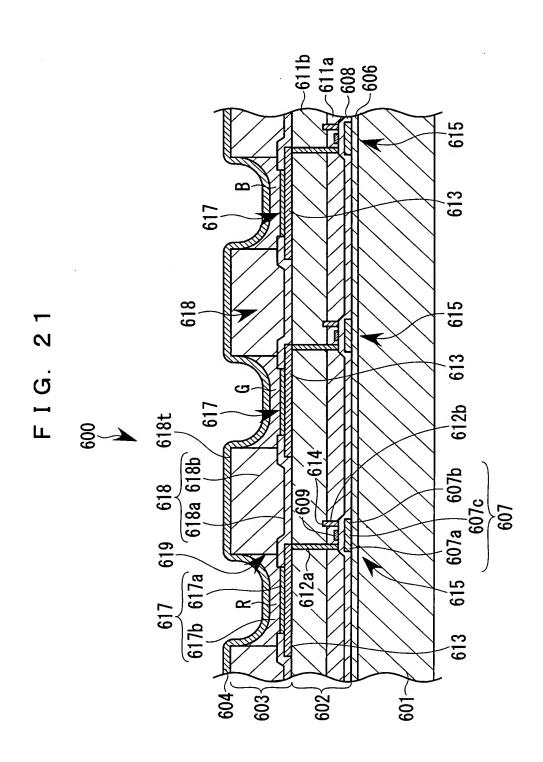
INTELLEMENT OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS; IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

FIG. 20



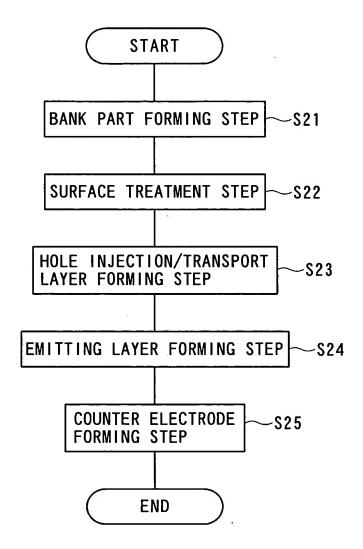
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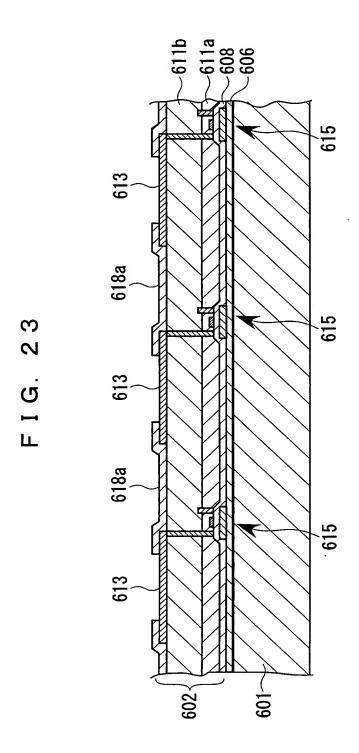
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

F I G. 22

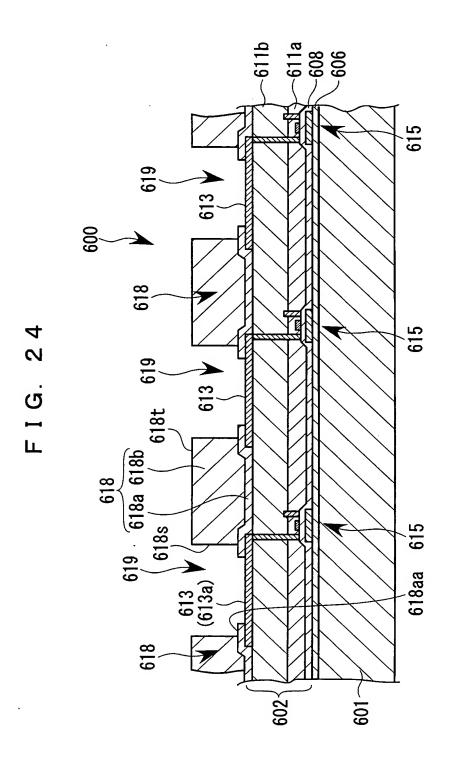


IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT
Inventor: Shinichi NAKAMURA
Atty. Ref.: 9319H-000586



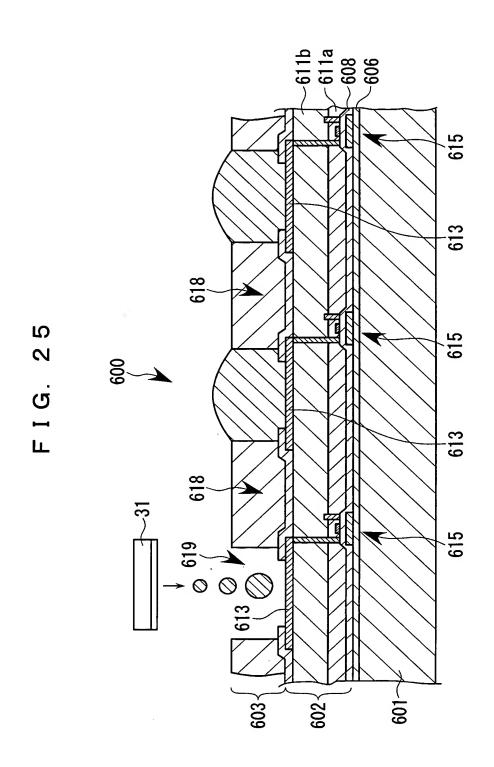
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Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



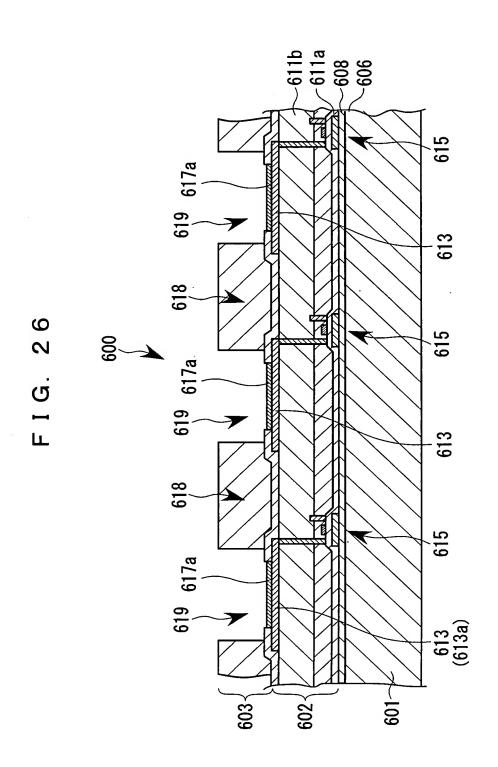
IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



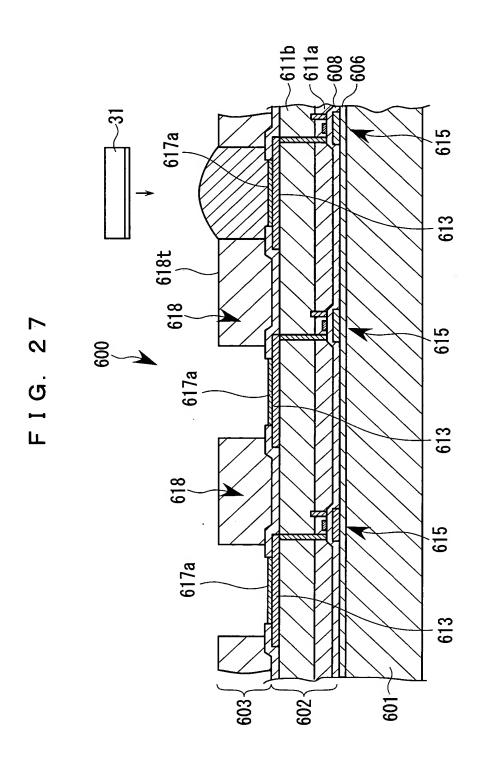
IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



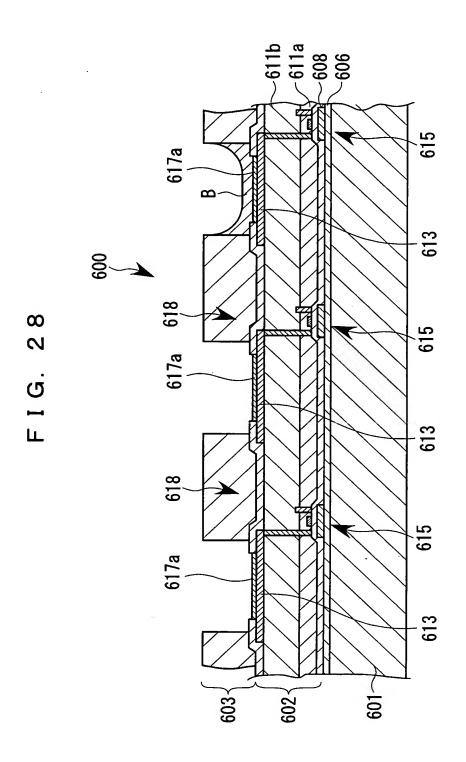
IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING
ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



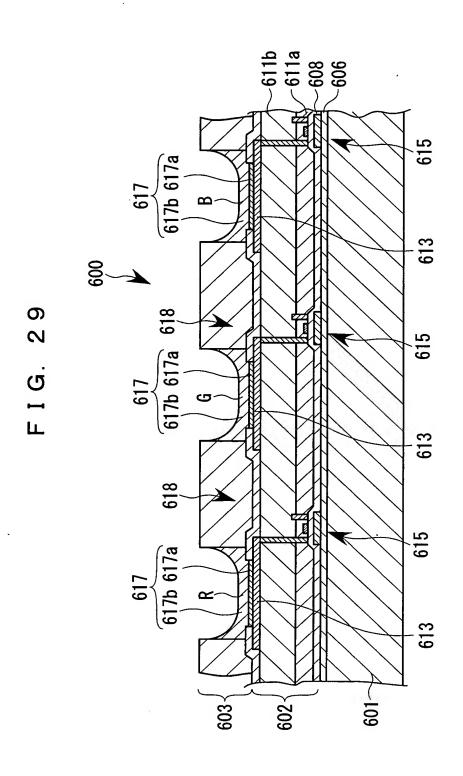
INTELEMENTATION OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS; IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



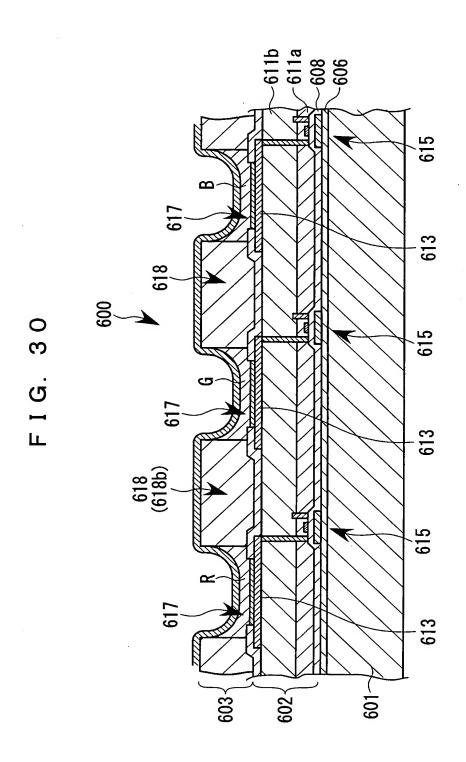
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Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



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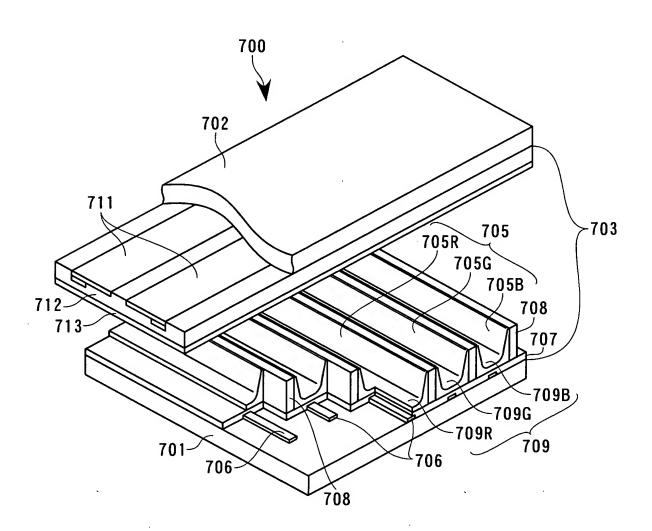
Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



Title: METHOD OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS; IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

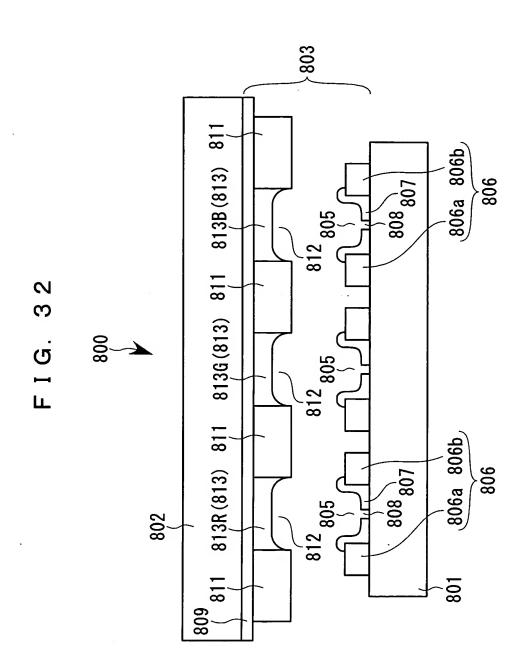
Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586

FIG. 31



Title: METHOD OF DETERMINING ABNORMALITY OF NOZZLES IN IMAGING APPARATUS; IMAGING APPARATUS; ELECTROOPTIC DEVICE; METHOD OF MANUFACTURING ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT

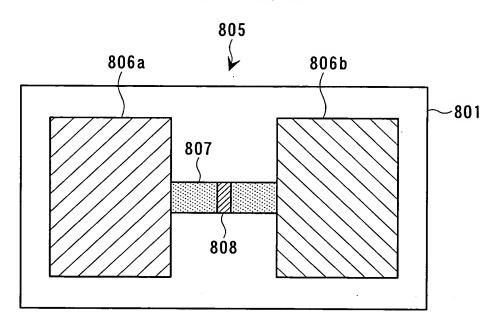
Inventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586



ELECTROOPTIC DEVICE; AND ELECTRONIC EQUIPMENT Inventor: Shinichi NAKAMURA

ventor: Shinichi NAKAMURA Atty. Ref.: 9319H-000586 33/33

F I G. 33A



F I G. 33B

